



XRD Application LAB

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2½D

Surface and Thin Film Analysis

Date sent:	
FROM:	
Institute / Company:	
E-mail / Telephone:	
Project No.:	
Type of Analysis:	

Code:	
Material:	
Precautions:	
Problem to solve:	

CODE:	Date of Reception:	Date of Data Collection:
Diffractometre: STADIP or PANalytical	Measurement:	Special Details:
Handled by:	Notes:	Results sent: